

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRR-h encoded:
				5 *
				6 * E677 VCP - VECTOR COMPARE DECIMAL
				7 *
				8 * James Wekel June 2024
				9 *****
				10
				11 *****
				12 *
				13 * basic instruction tests
				14 *
				15 *****
				16 * This program tests proper functioning of the z/arch E6 VRR-h vector
				17 * compare decimal. Exceptions are not tested.
				18 *
				19 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				20 * obvious coding errors. None of the tests are thorough. They are
				21 * NOT designed to test all aspects of any of the instructions.
				22 *
				23 *****
				24 *
				25 * *Testcase zvector-e6-15-comparedecimal: VECTOR E6 VRR-h instruction
				26 * *
				27 * * Zvector E6 tests for VRR-h encoded instruction:
				28 * *
				29 * * E677 VCP - VECTOR COMPARE DECIMAL
				30 * *
				31 * * # -----
				32 * * # This tests only the basic function of the instruction.
				33 * * # Exceptions are NOT tested.
				34 * * # -----
				35 * *
				36 * main size 2
				37 * numcpu 1
				38 * sysclear
				39 * archlvl z/Arch
				40 *
				41 * diag8cmd enable # (needed for messages to Hercules console)
				42 * loadcore "\$(testpath)/zvector-e6-15-comparedecimal.core" 0x0
				43 * diag8cmd disable # (reset back to default)
				44 *
				45 * *Done
				46 *
				47 *****
00000000		00000000	000019FF	49 ZVE6TST START 0
		00000000		50 USING ZVE6TST, R0 Low core addressability
				51
		00000140	00000000	52 SVOLDPSW EQU ZVE6TST+X' 140' z/Arch Supervisor call old PSW
00000000		00000000	000001A0	54 ORG ZVE6TST+X' 1A0'
000001A0	00000001 80000000			55 DC X' 0000000180000000' z/Architecture RESTART PSW

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				375 *****	
				376 * Macros to help build test tables	
				377 * -----	
				378 * VRR_H Macro to help build test tables	
				379 *****	
				380 MACRO	
				381 VRR_H &INST, &MB, &CC	
				382 . *	&INST - instruction under test
				383 . *	&CC - expected CC
				384 . *	
				385 LCLA &XCC(4) &CC has mask values for FAILED condition codes	
				386 &XCC(1) SETA 7	CC != 0
				387 &XCC(2) SETA 11	CC != 1
				388 &XCC(3) SETA 13	CC != 2
				389 &XCC(4) SETA 14	CC != 3
				390	
				391 GBLA &TNUM	
				392 &TNUM SETA &TNUM+1	
				393	
				394 DS 0FD	
				395 USING *, R5	base for test data and test routine
				396	
				397 T&TNUM DC A(X&TNUM)	address of test routine
				398 DC H' &TNUM	test number
				399 DC XL1' 00'	
				400 DC HL1' &MB'	m3
				401 DC HL1' &CC'	cc
				402 DC HL1' &XCC(&CC+1)'	cc failed mask
				403	
				404 DC CL8' &INST'	instruction name
				405	
				406 DC A(16)	result length
				407 REA&TNUM DC A(RE&TNUM)	result address
				408 . *	
				409 *	INSTRUCTION UNDER TEST ROUTINE
				410 X&TNUM DS 0F	
				411 VL V1, RE&TNUM	get V1 source
				412 VL V2, RE&TNUM+16	get V2 source
				413	
				414 &INST V1, V2, &MB	test instruction
				415	
				416 EPSW R2, R0	extract psw
				417 ST R2, CCPSW	to save CC
				418	
				419 BR R11	return
				420	
				421 RE&TNUM DC 0F	
				422 DROP R5	
				423	
				424 MEND	

426	*****		
427	* PTTABLE Macro to generate table of pointers to individual tests		
428	*****		
429			
430		MACRO	
431		PTTABLE	
432		GBLA	&TNUM
433		LCLA	&CUR
434	&CUR	SETA	1
435	. *		
436	TTABLE	DS	OF
437	. LOOP	ANOP	
438	. *		
439		DC	A(T&CUR) address of test
440	. *		
441	&CUR	SETA	&CUR+1
442		AIF	(&CUR LE &TNUM) . LOOP
443	*		
444		DC	A(0) END OF TABLE
445		DC	A(0)
446	. *		
447		MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				449 *****	
				450 * E6 VRR_H tests	
				451 *****	
00001148		00000000	000019FF	452 ZVE6TST CSECT ,	
				453 DS 0F	
				455 PRINT DATA	
				456 *	
				457 * E677 VCP - VECTOR COMPARE DECIMAL	
				458 * VRR_H instr, m3, cc	
				459 * followed by	
				460 * v1 - 16 byte source	
				461 * v2 - 16 byte source	
				462 *	
				463 * -----	
				464 * VCP - VECTOR COMPARE DECIMAL	
				465 * -----	
				466 * VCP simple	m3= 0 (P1=0, P2=0)
				467 *	m3= 4 (P1=0, P2=1)
				468 *	m3= 8 (P1=1, P2=0)
				469 *	m3=12 (P1=1, P2=1)
				470 * m3= 0 (P1=0, P2=0)	
00001148				471 VRR_H VCP, 0, 0	
00001148		00001148		472+ DS 0FD	
00001148	00001164			473+ USING *, R5	base for test data and test routine
0000114C	0001			474+T1 DC A(X1)	address of test routine
0000114E	00			475+ DC H' 1'	test number
0000114F	00			476+ DC XL1' 00'	
00001150	00			477+ DC HL1' 0'	m3
00001151	07			478+ DC HL1' 0'	cc
00001152	E5C3D740 40404040			479+ DC HL1' 7'	cc failed mask
0000115C	00000010			480+ DC CL8' VCP'	instruction name
00001160	00001180			481+ DC A(16)	result length
				482+REA1 DC A(RE1)	result address
				483+*	INSTRUCTION UNDER TEST ROUTINE
00001164				484+X1 DS 0F	
00001164	E710 5038 0006		00001180	485+ VL V1, RE1	get V1 source
0000116A	E720 5048 0006		00001190	486+ VL V2, RE1+16	get V2 source
00001170	E601 2000 0077			487+ VCP V1, V2, 0	test instruction
00001176	B98D 0020			488+ EPSW R2, R0	exptract psw
0000117A	5020 8E98		00001098	489+ ST R2, CCPSW	to save CC
0000117E	07FB			490+ BR R11	return
00001180				491+RE1 DC 0F	
00001180				492+ DROP R5	
00001180	00000000 00000000			493 DC XL16' 000000000000000000001234500000000D'	V1 source
00001188	00123450 0000000D				
00001190	00000000 00000000			494 DC XL16' 000000000000000000001234500000000D'	V2 source
00001198	00123450 0000000D				
				495	
000011A0				496 VRR_H VCP, 0, 0	
000011A0		000011A0		497+ DS 0FD	
000011A0	000011BC			498+ USING *, R5	base for test data and test routine
000011A4	0002			499+T2 DC A(X2)	address of test routine
000011A6	00			500+ DC H' 2'	test number
				501+ DC XL1' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011A7	00			502+	DC	HL1' 0'	m3
000011A8	00			503+	DC	HL1' 0'	cc
000011A9	07			504+	DC	HL1' 7'	cc failed mask
000011AA	E5C3D740 40404040			505+	DC	CL8' VCP'	instruction name
000011B4	00000010			506+	DC	A(16)	result length
000011B8	000011D8			507+REA2	DC	A(RE2)	result address
				508+*			INSTRUCTION UNDER TEST ROUTINE
000011BC				509+X2	DS	0F	
000011BC	E710 5038 0006		000011D8	510+	VL	V1, RE2	get V1 source
000011C2	E720 5048 0006		000011E8	511+	VL	V2, RE2+16	get V2 source
000011C8	E601 2000 0077			512+	VCP	V1, V2, 0	test instruction
000011CE	B98D 0020			513+	EPSW	R2, R0	exptract psw
000011D2	5020 8E98		00001098	514+	ST	R2, CCPSW	to save CC
000011D6	07FB			515+	BR	R11	return
000011D8				516+RE2	DC	0F	
000011D8				517+	DROP	R5	
000011D8	00000990 00000000			518	DC	XL16' 000009900000000000001234500000000C'	V1 source
000011E0	00123450 0000000C						
000011E8	00000990 00000000			519	DC	XL16' 000009900000000000001234500000000C'	V2 source
000011F0	00123450 0000000C						
				520			
				521	VRR_H	VCP, 0, 1	
000011F8				522+	DS	0FD	
000011F8		000011F8		523+	USING	*, R5	base for test data and test routine
000011F8	00001214			524+T3	DC	A(X3)	address of test routine
000011FC	0003			525+	DC	H' 3'	test number
000011FE	00			526+	DC	XL1' 00'	
000011FF	00			527+	DC	HL1' 0'	m3
00001200	01			528+	DC	HL1' 1'	cc
00001201	0B			529+	DC	HL1' 11'	cc failed mask
00001202	E5C3D740 40404040			530+	DC	CL8' VCP'	instruction name
0000120C	00000010			531+	DC	A(16)	result length
00001210	00001230			532+REA3	DC	A(RE3)	result address
				533+*			INSTRUCTION UNDER TEST ROUTINE
00001214				534+X3	DS	0F	
00001214	E710 9030 0006		00001230	535+	VL	V1, RE3	get V1 source
0000121A	E720 9040 0006		00001240	536+	VL	V2, RE3+16	get V2 source
00001220	E601 2000 0077			537+	VCP	V1, V2, 0	test instruction
00001226	B98D 0020			538+	EPSW	R2, R0	exptract psw
0000122A	5020 8E98		00001098	539+	ST	R2, CCPSW	to save CC
0000122E	07FB			540+	BR	R11	return
00001230				541+RE3	DC	0F	
00001230				542+	DROP	R5	
00001230	00000000 00000000			543	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001238	00123450 0000000D						
00001240	00000000 00000000			544	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001248	00123450 0000000C						
				545			
				546	VRR_H	VCP, 0, 1	
00001250				547+	DS	0FD	
00001250		00001250		548+	USING	*, R5	base for test data and test routine
00001250	0000126C			549+T4	DC	A(X4)	address of test routine
00001254	0004			550+	DC	H' 4'	test number
00001256	00			551+	DC	XL1' 00'	
00001257	00			552+	DC	HL1' 0'	m3
00001258	01			553+	DC	HL1' 1'	cc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001259	0B			554+	DC	HL1' 11'	cc failed mask
0000125A	E5C3D740 40404040			555+	DC	CL8' VCP'	instruction name
00001264	00000010			556+	DC	A(16)	result length
00001268	00001288			557+REA4	DC	A(RE4)	result address
				558+*			INSTRUCTION UNDER TEST ROUTINE
0000126C				559+X4	DS	0F	
0000126C	E710 5038 0006		00001288	560+	VL	V1, RE4	get V1 source
00001272	E720 5048 0006		00001298	561+	VL	V2, RE4+16	get V2 source
00001278	E601 2000 0077			562+	VCP	V1, V2, 0	test instruction
0000127E	B98D 0020			563+	EPSW	R2, R0	exptract psw
00001282	5020 8E98		00001098	564+	ST	R2, CCPSW	to save CC
00001286	07FB			565+	BR	R11	return
00001288				566+RE4	DC	0F	
00001288				567+	DROP	R5	
00001288	00000990 00000000			568	DC	XL16' 000009900000000000000234500000000C'	V1 source
00001290	00023450 0000000C						
00001298	00000990 00000000			569	DC	XL16' 000009900000000000001234500000000C'	V2 source
000012A0	00123450 0000000C						
				570			
				571	VRR_H	VCP, 0, 2	
000012A8				572+	DS	0FD	
000012A8		000012A8		573+	USING	*, R5	base for test data and test routine
000012A8	000012C4			574+T5	DC	A(X5)	address of test routine
000012AC	0005			575+	DC	H' 5'	test number
000012AE	00			576+	DC	XL1' 00'	
000012AF	00			577+	DC	HL1' 0'	m3
000012B0	02			578+	DC	HL1' 2'	cc
000012B1	0D			579+	DC	HL1' 13'	cc failed mask
000012B2	E5C3D740 40404040			580+	DC	CL8' VCP'	instruction name
000012BC	00000010			581+	DC	A(16)	result length
000012C0	000012E0			582+REA5	DC	A(RE5)	result address
				583+*			INSTRUCTION UNDER TEST ROUTINE
000012C4				584+X5	DS	0F	
000012C4	E710 5038 0006		000012E0	585+	VL	V1, RE5	get V1 source
000012CA	E720 5048 0006		000012F0	586+	VL	V2, RE5+16	get V2 source
000012D0	E601 2000 0077			587+	VCP	V1, V2, 0	test instruction
000012D6	B98D 0020			588+	EPSW	R2, R0	exptract psw
000012DA	5020 8E98		00001098	589+	ST	R2, CCPSW	to save CC
000012DE	07FB			590+	BR	R11	return
000012E0				591+RE5	DC	0F	
000012E0				592+	DROP	R5	
000012E0	00000000 00000000			593	DC	XL16' 000000000000000000001234500000000C'	V1 source
000012E8	00123450 0000000C						
000012F0	00000000 00000000			594	DC	XL16' 000000000000000000001234500000000D'	V2 source
000012F8	00123450 0000000D						
				595			
				596	VRR_H	VCP, 0, 2	
00001300				597+	DS	0FD	
00001300		00001300		598+	USING	*, R5	base for test data and test routine
00001300	0000131C			599+T6	DC	A(X6)	address of test routine
00001304	0006			600+	DC	H' 6'	test number
00001306	00			601+	DC	XL1' 00'	
00001307	00			602+	DC	HL1' 0'	m3
00001308	02			603+	DC	HL1' 2'	cc
00001309	0D			604+	DC	HL1' 13'	cc failed mask
0000130A	E5C3D740 40404040			605+	DC	CL8' VCP'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001314	00000010			606+	DC	A(16)	result length
00001318	00001338			607+REA6	DC	A(RE6)	result address
				608+*			INSTRUCTION UNDER TEST ROUTINE
0000131C				609+X6	DS	0F	
0000131C	E710 5038 0006		00001338	610+	VL	V1, RE6	get V1 source
00001322	E720 5048 0006		00001348	611+	VL	V2, RE6+16	get V2 source
00001328	E601 2000 0077			612+	VCP	V1, V2, 0	test instruction
0000132E	B98D 0020			613+	EPSW	R2, R0	exptract psw
00001332	5020 8E98		00001098	614+	ST	R2, CCPSW	to save CC
00001336	07FB			615+	BR	R11	return
00001338				616+RE6	DC	0F	
00001338				617+	DROP	R5	
00001338	00000990 00000000			618	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001340	00123450 0000000C						
00001348	00000990 00000000			619	DC	XL16' 000009900000000000000234500000000C'	V2 source
00001350	00023450 0000000C						
				620			
				621 * m3= 4	(P1=0, P2=1)		
				622	VRR_H VCP, 4, 1		
00001358		00001358		623+	DS	0FD	
00001358				624+	USING *, R5		base for test data and test routine
00001358	00001374			625+T7	DC	A(X7)	address of test routine
0000135C	0007			626+	DC	H' 7'	test number
0000135E	00			627+	DC	XL1' 00'	
0000135F	04			628+	DC	HL1' 4'	m3
00001360	01			629+	DC	HL1' 1'	cc
00001361	0B			630+	DC	HL1' 11'	cc failed mask
00001362	E5C3D740 40404040			631+	DC	CL8' VCP'	instruction name
0000136C	00000010			632+	DC	A(16)	result length
00001370	00001390			633+REA7	DC	A(RE7)	result address
				634+*			INSTRUCTION UNDER TEST ROUTINE
00001374				635+X7	DS	0F	
00001374	E710 5038 0006		00001390	636+	VL	V1, RE7	get V1 source
0000137A	E720 5048 0006		000013A0	637+	VL	V2, RE7+16	get V2 source
00001380	E601 2040 0077			638+	VCP	V1, V2, 4	test instruction
00001386	B98D 0020			639+	EPSW	R2, R0	exptract psw
0000138A	5020 8E98		00001098	640+	ST	R2, CCPSW	to save CC
0000138E	07FB			641+	BR	R11	return
00001390				642+RE7	DC	0F	
00001390				643+	DROP	R5	
00001390	00000000 00000000			644	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001398	00123450 0000000D						
000013A0	00000000 00000000			645	DC	XL16' 000000000000000000001234500000000D'	V2 source
000013A8	00123450 0000000D						
				646			
				647	VRR_H VCP, 4, 0		
000013B0		000013B0		648+	DS	0FD	
000013B0				649+	USING *, R5		base for test data and test routine
000013B0	000013CC			650+T8	DC	A(X8)	address of test routine
000013B4	0008			651+	DC	H' 8'	test number
000013B6	00			652+	DC	XL1' 00'	
000013B7	04			653+	DC	HL1' 4'	m3
000013B8	00			654+	DC	HL1' 0'	cc
000013B9	07			655+	DC	HL1' 7'	cc failed mask
000013BA	E5C3D740 40404040			656+	DC	CL8' VCP'	instruction name
000013C4	00000010			657+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000013C8	000013E8			658+REA8	DC	A(RE8)	result address
				659+*			INSTRUCTION UNDER TEST ROUTINE
000013CC				660+X8	DS	0F	
000013CC	E710 5038 0006		000013E8	661+	VL	V1, RE8	get V1 source
000013D2	E720 5048 0006		000013F8	662+	VL	V2, RE8+16	get V2 source
000013D8	E601 2040 0077			663+	VCP	V1, V2, 4	test instruction
000013DE	B98D 0020			664+	EPSW	R2, R0	exptract psw
000013E2	5020 8E98		00001098	665+	ST	R2, CCPSW	to save CC
000013E6	07FB			666+	BR	R11	return
000013E8				667+RE8	DC	0F	
000013E8				668+	DROP	R5	
000013E8	00000990 00000000			669	DC	XL16' 000009900000000000001234500000000C'	V1 source
000013F0	00123450 0000000C						
000013F8	00000990 00000000			670	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001400	00123450 0000000C						
				671			
				672	VRR_H	VCP, 4, 1	
00001408				673+	DS	0FD	
00001408		00001408		674+	USING	*, R5	base for test data and test routine
00001408	00001424			675+T9	DC	A(X9)	address of test routine
0000140C	0009			676+	DC	H' 9'	test number
0000140E	00			677+	DC	XL1' 00'	
0000140F	04			678+	DC	HL1' 4'	m3
00001410	01			679+	DC	HL1' 1'	cc
00001411	0B			680+	DC	HL1' 11'	cc failed mask
00001412	E5C3D740 40404040			681+	DC	CL8' VCP'	instruction name
0000141C	00000010			682+	DC	A(16)	result length
00001420	00001440			683+REA9	DC	A(RE9)	result address
				684+*			INSTRUCTION UNDER TEST ROUTINE
00001424				685+X9	DS	0F	
00001424	E710 5038 0006		00001440	686+	VL	V1, RE9	get V1 source
0000142A	E720 5048 0006		00001450	687+	VL	V2, RE9+16	get V2 source
00001430	E601 2040 0077			688+	VCP	V1, V2, 4	test instruction
00001436	B98D 0020			689+	EPSW	R2, R0	exptract psw
0000143A	5020 8E98		00001098	690+	ST	R2, CCPSW	to save CC
0000143E	07FB			691+	BR	R11	return
00001440				692+RE9	DC	0F	
00001440				693+	DROP	R5	
00001440	00000000 00000000			694	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001448	00123450 0000000D						
00001450	00000000 00000000			695	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001458	00123450 0000000C						
				696			
				697	VRR_H	VCP, 4, 1	
00001460				698+	DS	0FD	
00001460		00001460		699+	USING	*, R5	base for test data and test routine
00001460	0000147C			700+T10	DC	A(X10)	address of test routine
00001464	000A			701+	DC	H' 10'	test number
00001466	00			702+	DC	XL1' 00'	
00001467	04			703+	DC	HL1' 4'	m3
00001468	01			704+	DC	HL1' 1'	cc
00001469	0B			705+	DC	HL1' 11'	cc failed mask
0000146A	E5C3D740 40404040			706+	DC	CL8' VCP'	instruction name
00001474	00000010			707+	DC	A(16)	result length
00001478	00001498			708+REA10	DC	A(RE10)	result address
				709+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000147C				710+X10	DS	0F	
0000147C	E710 5038 0006		00001498	711+	VL	V1, RE10	get V1 source
00001482	E720 5048 0006		000014A8	712+	VL	V2, RE10+16	get V2 source
00001488	E601 2040 0077			713+	VCP	V1, V2, 4	test instruction
0000148E	B98D 0020			714+	EPSW	R2, R0	exptract psw
00001492	5020 8E98		00001098	715+	ST	R2, CCPSW	to save CC
00001496	07FB			716+	BR	R11	return
00001498				717+RE10	DC	0F	
00001498				718+	DROP	R5	
00001498	00000990 00000000			719	DC	XL16' 000009900000000000000234500000000C'	V1 source
000014A0	00023450 0000000C						
000014A8	00000990 00000000			720	DC	XL16' 000009900000000000001234500000000C'	V2 source
000014B0	00123450 0000000C						
				721			
				722	VRR_H	VCP, 4, 0	
000014B8				723+	DS	0FD	
000014B8		000014B8		724+	USING	*, R5	base for test data and test routine
000014B8	000014D4			725+T11	DC	A(X11)	address of test routine
000014BC	000B			726+	DC	H' 11'	test number
000014BE	00			727+	DC	XL1' 00'	
000014BF	04			728+	DC	HL1' 4'	m3
000014C0	00			729+	DC	HL1' 0'	cc
000014C1	07			730+	DC	HL1' 7'	cc failed mask
000014C2	E5C3D740 40404040			731+	DC	CL8' VCP'	instruction name
000014CC	00000010			732+	DC	A(16)	result length
000014D0	000014F0			733+REA11	DC	A(RE11)	result address
				734+*			INSTRUCTION UNDER TEST ROUTINE
000014D4				735+X11	DS	0F	
000014D4	E710 5038 0006		000014F0	736+	VL	V1, RE11	get V1 source
000014DA	E720 5048 0006		00001500	737+	VL	V2, RE11+16	get V2 source
000014E0	E601 2040 0077			738+	VCP	V1, V2, 4	test instruction
000014E6	B98D 0020			739+	EPSW	R2, R0	exptract psw
000014EA	5020 8E98		00001098	740+	ST	R2, CCPSW	to save CC
000014EE	07FB			741+	BR	R11	return
000014F0				742+RE11	DC	0F	
000014F0				743+	DROP	R5	
000014F0	00000000 00000000			744	DC	XL16' 000000000000000000001234500000000C'	V1 source
000014F8	00123450 0000000C						
00001500	00000000 00000000			745	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001508	00123450 0000000D						
				746			
				747	VRR_H	VCP, 4, 2	
00001510				748+	DS	0FD	
00001510		00001510		749+	USING	*, R5	base for test data and test routine
00001510	0000152C			750+T12	DC	A(X12)	address of test routine
00001514	000C			751+	DC	H' 12'	test number
00001516	00			752+	DC	XL1' 00'	
00001517	04			753+	DC	HL1' 4'	m3
00001518	02			754+	DC	HL1' 2'	cc
00001519	0D			755+	DC	HL1' 13'	cc failed mask
0000151A	E5C3D740 40404040			756+	DC	CL8' VCP'	instruction name
00001524	00000010			757+	DC	A(16)	result length
00001528	00001548			758+REA12	DC	A(RE12)	result address
				759+*			INSTRUCTION UNDER TEST ROUTINE
0000152C				760+X12	DS	0F	
0000152C	E710 5038 0006		00001548	761+	VL	V1, RE12	get V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001532	E720 5048 0006		00001558	762+	VL	V2, RE12+16	get V2 source
00001538	E601 2040 0077			763+	VCP	V1, V2, 4	test instruction
0000153E	B98D 0020			764+	EPSW	R2, R0	exptrect psw
00001542	5020 8E98		00001098	765+	ST	R2, CCPSW	to save CC
00001546	07FB			766+	BR	R11	return
00001548				767+RE12	DC	0F	
00001548				768+	DROP	R5	
00001548	00000990 00000000			769	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001550	00123450 0000000C						
00001558	00000990 00000000			770	DC	XL16' 000009900000000000000234500000000C'	V2 source
00001560	00023450 0000000C						
				771			
				772 * m3= 8	(P1=1, P2=0)		
				773	VRR_H	VCP, 8, 2	
00001568				774+	DS	0FD	
00001568		00001568		775+	USING	*, R5	base for test data and test routine
00001568	00001584			776+T13	DC	A(X13)	address of test routine
0000156C	000D			777+	DC	H' 13'	test number
0000156E	00			778+	DC	XL1' 00'	
0000156F	08			779+	DC	HL1' 8'	m3
00001570	02			780+	DC	HL1' 2'	cc
00001571	0D			781+	DC	HL1' 13'	cc failed mask
00001572	E5C3D740 40404040			782+	DC	CL8' VCP'	instruction name
0000157C	00000010			783+	DC	A(16)	result length
00001580	000015A0			784+REA13	DC	A(RE13)	result address
				785+*			INSTRUCTION UNDER TEST ROUTINE
00001584				786+X13	DS	0F	
00001584	E710 5038 0006		000015A0	787+	VL	V1, RE13	get V1 source
0000158A	E720 5048 0006		000015B0	788+	VL	V2, RE13+16	get V2 source
00001590	E601 2080 0077			789+	VCP	V1, V2, 8	test instruction
00001596	B98D 0020			790+	EPSW	R2, R0	exptrect psw
0000159A	5020 8E98		00001098	791+	ST	R2, CCPSW	to save CC
0000159E	07FB			792+	BR	R11	return
000015A0				793+RE13	DC	0F	
000015A0				794+	DROP	R5	
000015A0	00000000 00000000			795	DC	XL16' 000000000000000000001234500000000D'	V1 source
000015A8	00123450 0000000D						
000015B0	00000000 00000000			796	DC	XL16' 000000000000000000001234500000000D'	V2 source
000015B8	00123450 0000000D						
				797			
				798	VRR_H	VCP, 8, 0	
000015C0				799+	DS	0FD	
000015C0		000015C0		800+	USING	*, R5	base for test data and test routine
000015C0	000015DC			801+T14	DC	A(X14)	address of test routine
000015C4	000E			802+	DC	H' 14'	test number
000015C6	00			803+	DC	XL1' 00'	
000015C7	08			804+	DC	HL1' 8'	m3
000015C8	00			805+	DC	HL1' 0'	cc
000015C9	07			806+	DC	HL1' 7'	cc failed mask
000015CA	E5C3D740 40404040			807+	DC	CL8' VCP'	instruction name
000015D4	00000010			808+	DC	A(16)	result length
000015D8	000015F8			809+REA14	DC	A(RE14)	result address
				810+*			INSTRUCTION UNDER TEST ROUTINE
000015DC				811+X14	DS	0F	
000015DC	E710 5038 0006		000015F8	812+	VL	V1, RE14	get V1 source
000015E2	E720 5048 0006		00001608	813+	VL	V2, RE14+16	get V2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000015E8	E601 2080 0077			814+	VCP	V1, V2, 8	test instruction
000015EE	B98D 0020			815+	EPSW	R2, R0	exptract psw
000015F2	5020 8E98		00001098	816+	ST	R2, CCPSW	to save CC
000015F6	07FB			817+	BR	R11	return
000015F8				818+RE14	DC	0F	
000015F8				819+	DROP	R5	
000015F8	00000990 00000000			820	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001600	00123450 0000000C						
00001608	00000990 00000000			821	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001610	00123450 0000000C						
				822			
00001618				823	VRR_H	VCP, 8, 0	
00001618		00001618		824+	DS	0FD	
00001618	00001634			825+	USING	*, R5	base for test data and test routine
0000161C	000F			826+T15	DC	A(X15)	address of test routine
0000161E	00			827+	DC	H' 15'	test number
0000161E	00			828+	DC	XL1' 00'	
0000161F	08			829+	DC	HL1' 8'	m3
00001620	00			830+	DC	HL1' 0'	cc
00001621	07			831+	DC	HL1' 7'	cc failed mask
00001622	E5C3D740 40404040			832+	DC	CL8' VCP'	instruction name
0000162C	00000010			833+	DC	A(16)	result length
00001630	00001650			834+REA15	DC	A(RE15)	result address
				835+*			INSTRUCTION UNDER TEST ROUTINE
00001634				836+X15	DS	0F	
00001634	E710 5038 0006		00001650	837+	VL	V1, RE15	get V1 source
0000163A	E720 5048 0006		00001660	838+	VL	V2, RE15+16	get V2 source
00001640	E601 2080 0077			839+	VCP	V1, V2, 8	test instruction
00001646	B98D 0020			840+	EPSW	R2, R0	exptract psw
0000164A	5020 8E98		00001098	841+	ST	R2, CCPSW	to save CC
0000164E	07FB			842+	BR	R11	return
00001650				843+RE15	DC	0F	
00001650				844+	DROP	R5	
00001650	00000000 00000000			845	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001658	00123450 0000000D						
00001660	00000000 00000000			846	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001668	00123450 0000000C						
				847			
00001670				848	VRR_H	VCP, 8, 1	
00001670		00001670		849+	DS	0FD	
00001670	0000168C			850+	USING	*, R5	base for test data and test routine
00001674	0010			851+T16	DC	A(X16)	address of test routine
00001674	00			852+	DC	H' 16'	test number
00001676	00			853+	DC	XL1' 00'	
00001677	08			854+	DC	HL1' 8'	m3
00001678	01			855+	DC	HL1' 1'	cc
00001679	0B			856+	DC	HL1' 11'	cc failed mask
0000167A	E5C3D740 40404040			857+	DC	CL8' VCP'	instruction name
00001684	00000010			858+	DC	A(16)	result length
00001688	000016A8			859+REA16	DC	A(RE16)	result address
				860+*			INSTRUCTION UNDER TEST ROUTINE
0000168C				861+X16	DS	0F	
0000168C	E710 5038 0006		000016A8	862+	VL	V1, RE16	get V1 source
00001692	E720 5048 0006		000016B8	863+	VL	V2, RE16+16	get V2 source
00001698	E601 2080 0077			864+	VCP	V1, V2, 8	test instruction
0000169E	B98D 0020			865+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016A2	5020 8E98		00001098	866+	ST	R2, CCPSW	to save CC
000016A6	07FB			867+	BR	R11	return
000016A8				868+RE16	DC	0F	
000016A8				869+	DROP	R5	
000016A8	00000990 00000000			870	DC	XL16' 000009900000000000000234500000000C'	V1 source
000016B0	00023450 0000000C						
000016B8	00000990 00000000		871		DC	XL16' 000009900000000000001234500000000C'	V2 source
000016C0	00123450 0000000C						
			872				
			873		VRR_H	VCP, 8, 2	
000016C8			874+		DS	0FD	
000016C8		000016C8	875+		USING	*, R5	base for test data and test routine
000016C8	000016E4		876+T17		DC	A(X17)	address of test routine
000016CC	0011		877+		DC	H' 17'	test number
000016CE	00		878+		DC	XL1' 00'	
000016CF	08		879+		DC	HL1' 8'	m3
000016D0	02		880+		DC	HL1' 2'	cc
000016D1	0D		881+		DC	HL1' 13'	cc failed mask
000016D2	E5C3D740 40404040		882+		DC	CL8' VCP'	instruction name
000016DC	00000010		883+		DC	A(16)	result length
000016E0	00001700		884+REA17		DC	A(RE17)	result address
			885+*				INSTRUCTION UNDER TEST ROUTINE
000016E4			886+X17		DS	0F	
000016E4	E710 5038 0006		887+		VL	V1, RE17	get V1 source
000016EA	E720 5048 0006	00001700	888+		VL	V2, RE17+16	get V2 source
000016F0	E601 2080 0077		889+		VCP	V1, V2, 8	test instruction
000016F6	B98D 0020		890+		EPSW	R2, R0	extract psw
000016FA	5020 8E98	00001098	891+		ST	R2, CCPSW	to save CC
000016FE	07FB		892+		BR	R11	return
00001700			893+RE17		DC	0F	
00001700			894+		DROP	R5	
00001700	00000000 00000000		895		DC	XL16' 000000000000000000001234500000000C'	V1 source
00001708	00123450 0000000C						
00001710	00000000 00000000		896		DC	XL16' 000000000000000000001234500000000D'	V2 source
00001718	00123450 0000000D						
			897				
			898		VRR_H	VCP, 8, 2	
00001720			899+		DS	0FD	
00001720		00001720	900+		USING	*, R5	base for test data and test routine
00001720	0000173C		901+T18		DC	A(X18)	address of test routine
00001724	0012		902+		DC	H' 18'	test number
00001726	00		903+		DC	XL1' 00'	
00001727	08		904+		DC	HL1' 8'	m3
00001728	02		905+		DC	HL1' 2'	cc
00001729	0D		906+		DC	HL1' 13'	cc failed mask
0000172A	E5C3D740 40404040		907+		DC	CL8' VCP'	instruction name
00001734	00000010		908+		DC	A(16)	result length
00001738	00001758		909+REA18		DC	A(RE18)	result address
			910+*				INSTRUCTION UNDER TEST ROUTINE
0000173C			911+X18		DS	0F	
0000173C	E710 5038 0006		912+		VL	V1, RE18	get V1 source
00001742	E720 5048 0006	00001768	913+		VL	V2, RE18+16	get V2 source
00001748	E601 2080 0077		914+		VCP	V1, V2, 8	test instruction
0000174E	B98D 0020		915+		EPSW	R2, R0	extract psw
00001752	5020 8E98	00001098	916+		ST	R2, CCPSW	to save CC
00001756	07FB		917+		BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001758				918+RE18	DC	0F
00001758				919+	DROP	R5
00001758	00000990 00000000			920	DC	XL16' 000009900000000000001234500000000C' V1 source
00001760	00123450 0000000C					
00001768	00000990 00000000			921	DC	XL16' 00000990000000000000234500000000C' V2 source
00001770	00023450 0000000C					
				922		
				923 * mB=12	(P1=1, P2=1)	
				924	VRR_H	VCP, 12, 0
00001778		00001778		925+	DS	0FD
00001778				926+	USING	*, R5
00001778	00001794			927+T19	DC	A(X19)
0000177C	0013			928+	DC	H' 19'
0000177E	00			929+	DC	XL1' 00'
0000177F	0C			930+	DC	HL1' 12'
00001780	00			931+	DC	HL1' 0'
00001781	07			932+	DC	HL1' 7'
00001782	E5C3D740 40404040			933+	DC	CL8' VCP'
0000178C	00000010			934+	DC	A(16)
00001790	000017B0			935+REA19	DC	A(RE19)
				936+*		INSTRUCTION UNDER TEST ROUTINE
00001794				937+X19	DS	0F
00001794	E710 5038 0006		000017B0	938+	VL	V1, RE19
0000179A	E720 5048 0006		000017C0	939+	VL	V2, RE19+16
000017A0	E601 20C0 0077			940+	VCP	V1, V2, 12
000017A6	B98D 0020			941+	EPSW	R2, R0
000017AA	5020 8E98		00001098	942+	ST	R2, CCPSW
000017AE	07FB			943+	BR	R11
000017B0				944+RE19	DC	0F
000017B0				945+	DROP	R5
000017B0	00000000 00000000			946	DC	XL16' 000000000000000000001234500000000D' V1 source
000017B8	00123450 0000000D					
000017C0	00000000 00000000			947	DC	XL16' 000000000000000000001234500000000D' V2 source
000017C8	00123450 0000000D					
				948		
				949	VRR_H	VCP, 12, 0
000017D0		000017D0		950+	DS	0FD
000017D0				951+	USING	*, R5
000017D0	000017EC			952+T20	DC	A(X20)
000017D4	0014			953+	DC	H' 20'
000017D6	00			954+	DC	XL1' 00'
000017D7	0C			955+	DC	HL1' 12'
000017D8	00			956+	DC	HL1' 0'
000017D9	07			957+	DC	HL1' 7'
000017DA	E5C3D740 40404040			958+	DC	CL8' VCP'
000017E4	00000010			959+	DC	A(16)
000017E8	00001808			960+REA20	DC	A(RE20)
				961+*		INSTRUCTION UNDER TEST ROUTINE
000017EC				962+X20	DS	0F
000017EC	E710 5038 0006		00001808	963+	VL	V1, RE20
000017F2	E720 5048 0006		00001818	964+	VL	V2, RE20+16
000017F8	E601 20C0 0077			965+	VCP	V1, V2, 12
000017FE	B98D 0020			966+	EPSW	R2, R0
00001802	5020 8E98		00001098	967+	ST	R2, CCPSW
00001806	07FB			968+	BR	R11
00001808				969+RE20	DC	0F

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001808				970+	DROP R5	
00001808	00000990 00000000			971	DC	XL16' 000009900000000000001234500000000C' V1 source
00001810	00123450 0000000C					
00001818	00000990 00000000			972	DC	XL16' 000009900000000000001234500000000C' V2 source
00001820	00123450 0000000C					
				973		
				974	VRR_H VCP, 12, 0	
00001828				975+	DS OFD	
00001828		00001828		976+	USING *, R5	base for test data and test routine
00001828	00001844			977+T21	DC A(X21)	address of test routine
0000182C	0015			978+	DC H' 21'	test number
0000182E	00			979+	DC XL1' 00'	
0000182F	0C			980+	DC HL1' 12'	m3
00001830	00			981+	DC HL1' 0'	cc
00001831	07			982+	DC HL1' 7'	cc failed mask
00001832	E5C3D740 40404040			983+	DC CL8' VCP'	instruction name
0000183C	00000010			984+	DC A(16)	result length
00001840	00001860			985+REA21	DC A(RE21)	result address
				986+*		INSTRUCTION UNDER TEST ROUTINE
00001844				987+X21	DS OF	
00001844	E710 5038 0006		00001860	988+	VL V1, RE21	get V1 source
0000184A	E720 5048 0006		00001870	989+	VL V2, RE21+16	get V2 source
00001850	E601 20C0 0077			990+	VCP V1, V2, 12	test instruction
00001856	B98D 0020			991+	EPSW R2, R0	exptract psw
0000185A	5020 8E98		00001098	992+	ST R2, CCPSW	to save CC
0000185E	07FB			993+	BR R11	return
00001860				994+RE21	DC OF	
00001860				995+	DROP R5	
00001860	00000000 00000000			996	DC	XL16' 000000000000000000001234500000000D' V1 source
00001868	00123450 0000000D					
00001870	00000000 00000000			997	DC	XL16' 000000000000000000001234500000000C' V2 source
00001878	00123450 0000000C					
				998		
				999	VRR_H VCP, 12, 1	
00001880				1000+	DS OFD	
00001880		00001880		1001+	USING *, R5	base for test data and test routine
00001880	0000189C			1002+T22	DC A(X22)	address of test routine
00001884	0016			1003+	DC H' 22'	test number
00001886	00			1004+	DC XL1' 00'	
00001887	0C			1005+	DC HL1' 12'	m3
00001888	01			1006+	DC HL1' 1'	cc
00001889	0B			1007+	DC HL1' 11'	cc failed mask
0000188A	E5C3D740 40404040			1008+	DC CL8' VCP'	instruction name
00001894	00000010			1009+	DC A(16)	result length
00001898	000018B8			1010+REA22	DC A(RE22)	result address
				1011+*		INSTRUCTION UNDER TEST ROUTINE
0000189C				1012+X22	DS OF	
0000189C	E710 5038 0006		000018B8	1013+	VL V1, RE22	get V1 source
000018A2	E720 5048 0006		000018C8	1014+	VL V2, RE22+16	get V2 source
000018A8	E601 20C0 0077			1015+	VCP V1, V2, 12	test instruction
000018AE	B98D 0020			1016+	EPSW R2, R0	exptract psw
000018B2	5020 8E98		00001098	1017+	ST R2, CCPSW	to save CC
000018B6	07FB			1018+	BR R11	return
000018B8				1019+RE22	DC OF	
000018B8				1020+	DROP R5	
000018B8	00000990 00000000			1021	DC	XL16' 00000990000000000000234500000000C' V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000018C0	00023450 0000000C						
000018C8	00000990 00000000			1022	DC	XL16' 000009900000000000001234500000000C'	V2 source
000018D0	00123450 0000000C						
				1023			
				1024	VRR_H	VCP, 12, 0	
000018D8				1025+	DS	OFD	
000018D8		000018D8		1026+	USING	*, R5	base for test data and test routine
000018D8	000018F4			1027+T23	DC	A(X23)	address of test routine
000018DC	0017			1028+	DC	H' 23'	test number
000018DE	00			1029+	DC	XL1' 00'	
000018DF	0C			1030+	DC	HL1' 12'	m3
000018E0	00			1031+	DC	HL1' 0'	cc
000018E1	07			1032+	DC	HL1' 7'	cc failed mask
000018E2	E5C3D740 40404040			1033+	DC	CL8' VCP'	instruction name
000018EC	00000010			1034+	DC	A(16)	result length
000018F0	00001910			1035+REA23	DC	A(RE23)	result address
				1036+*			INSTRUCTION UNDER TEST ROUTINE
000018F4				1037+X23	DS	OF	
000018F4	E710 5038 0006		00001910	1038+	VL	V1, RE23	get V1 source
000018FA	E720 5048 0006		00001920	1039+	VL	V2, RE23+16	get V2 source
00001900	E601 20C0 0077			1040+	VCP	V1, V2, 12	test instruction
00001906	B98D 0020			1041+	EPSW	R2, R0	exptract psw
0000190A	5020 8E98		00001098	1042+	ST	R2, CCPSW	to save CC
0000190E	07FB			1043+	BR	R11	return
00001910				1044+RE23	DC	OF	
00001910				1045+	DROP	R5	
00001910	00000000 00000000			1046	DC	XL16' 000000000000000000001234500000000C'	V1 source
00001918	00123450 0000000C						
00001920	00000000 00000000			1047	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001928	00123450 0000000D						
				1048			
				1049	VRR_H	VCP, 12, 2	
00001930				1050+	DS	OFD	
00001930		00001930		1051+	USING	*, R5	base for test data and test routine
00001930	0000194C			1052+T24	DC	A(X24)	address of test routine
00001934	0018			1053+	DC	H' 24'	test number
00001936	00			1054+	DC	XL1' 00'	
00001937	0C			1055+	DC	HL1' 12'	m3
00001938	02			1056+	DC	HL1' 2'	cc
00001939	0D			1057+	DC	HL1' 13'	cc failed mask
0000193A	E5C3D740 40404040			1058+	DC	CL8' VCP'	instruction name
00001944	00000010			1059+	DC	A(16)	result length
00001948	00001968			1060+REA24	DC	A(RE24)	result address
				1061+*			INSTRUCTION UNDER TEST ROUTINE
0000194C				1062+X24	DS	OF	
0000194C	E710 5038 0006		00001968	1063+	VL	V1, RE24	get V1 source
00001952	E720 5048 0006		00001978	1064+	VL	V2, RE24+16	get V2 source
00001958	E601 20C0 0077			1065+	VCP	V1, V2, 12	test instruction
0000195E	B98D 0020			1066+	EPSW	R2, R0	exptract psw
00001962	5020 8E98		00001098	1067+	ST	R2, CCPSW	to save CC
00001966	07FB			1068+	BR	R11	return
00001968				1069+RE24	DC	OF	
00001968				1070+	DROP	R5	
00001968	00000990 00000000			1071	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001970	00123450 0000000C						
00001978	00000990 00000000			1072	DC	XL16' 00000990000000000000234500000000C'	V2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
00001980	00023450 0000000C			1073
00001988	00000000			1074
0000198C	00000000			1075
				1076 *
				1077 * table of pointers to individual load test
				1078 *
00001990				1079 E6TESTS DS OF
				1080 PTTABLE
00001990				1081+TTABLE DS OF
00001990	00001148			1082+ DC A(T1) address of test
00001994	000011A0			1083+ DC A(T2) address of test
00001998	000011F8			1084+ DC A(T3) address of test
0000199C	00001250			1085+ DC A(T4) address of test
000019A0	000012A8			1086+ DC A(T5) address of test
000019A4	00001300			1087+ DC A(T6) address of test
000019A8	00001358			1088+ DC A(T7) address of test
000019AC	000013B0			1089+ DC A(T8) address of test
000019B0	00001408			1090+ DC A(T9) address of test
000019B4	00001460			1091+ DC A(T10) address of test
000019B8	000014B8			1092+ DC A(T11) address of test
000019BC	00001510			1093+ DC A(T12) address of test
000019C0	00001568			1094+ DC A(T13) address of test
000019C4	000015C0			1095+ DC A(T14) address of test
000019C8	00001618			1096+ DC A(T15) address of test
000019CC	00001670			1097+ DC A(T16) address of test
000019D0	000016C8			1098+ DC A(T17) address of test
000019D4	00001720			1099+ DC A(T18) address of test
000019D8	00001778			1100+ DC A(T19) address of test
000019DC	000017D0			1101+ DC A(T20) address of test
000019E0	00001828			1102+ DC A(T21) address of test
000019E4	00001880			1103+ DC A(T22) address of test
000019E8	000018D8			1104+ DC A(T23) address of test
000019EC	00001930			1105+ DC A(T24) address of test
				1106+*
000019F0	00000000			1107+ DC A(0) END OF TABLE
000019F4	00000000			1108+ DC A(0)
				1109
000019F8	00000000			1110 DC F' 0' END OF TABLE
000019FC	00000000			1111 DC F' 0'

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT				
					1113	*****			
					1114	*	Register equates		
					1115	*****			
			00000000	00000001	1117	R0	EQU	0	
			00000001	00000001	1118	R1	EQU	1	
			00000002	00000001	1119	R2	EQU	2	
			00000003	00000001	1120	R3	EQU	3	
			00000004	00000001	1121	R4	EQU	4	
			00000005	00000001	1122	R5	EQU	5	
			00000006	00000001	1123	R6	EQU	6	
			00000007	00000001	1124	R7	EQU	7	
			00000008	00000001	1125	R8	EQU	8	
			00000009	00000001	1126	R9	EQU	9	
			0000000A	00000001	1127	R10	EQU	10	
			0000000B	00000001	1128	R11	EQU	11	
			0000000C	00000001	1129	R12	EQU	12	
			0000000D	00000001	1130	R13	EQU	13	
			0000000E	00000001	1131	R14	EQU	14	
			0000000F	00000001	1132	R15	EQU	15	
					1134	*****			
					1135	*	Register equates		
					1136	*****			
			00000000	00000001	1138	V0	EQU	0	
			00000001	00000001	1139	V1	EQU	1	
			00000002	00000001	1140	V2	EQU	2	
			00000003	00000001	1141	V3	EQU	3	
			00000004	00000001	1142	V4	EQU	4	
			00000005	00000001	1143	V5	EQU	5	
			00000006	00000001	1144	V6	EQU	6	
			00000007	00000001	1145	V7	EQU	7	
			00000008	00000001	1146	V8	EQU	8	
			00000009	00000001	1147	V9	EQU	9	
			0000000A	00000001	1148	V10	EQU	10	
			0000000B	00000001	1149	V11	EQU	11	
			0000000C	00000001	1150	V12	EQU	12	
			0000000D	00000001	1151	V13	EQU	13	
			0000000E	00000001	1152	V14	EQU	14	
			0000000F	00000001	1153	V15	EQU	15	
			00000010	00000001	1154	V16	EQU	16	
			00000011	00000001	1155	V17	EQU	17	
			00000012	00000001	1156	V18	EQU	18	
			00000013	00000001	1157	V19	EQU	19	
			00000014	00000001	1158	V20	EQU	20	
			00000015	00000001	1159	V21	EQU	21	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES														
BEGIN	I	00000200	2	90	56	87	88												
CC	U	00000008	1	361	156														
CCFOUND	X	000010A0	1	333	143	163													
CCMASK	U	00000009	1	362	123														
CCMSG	U	00000258	1	136	130														
CCPRTEXP	C	00001047	1	313	160														
CCPRTGOT	C	00001057	1	316	167														
CCPRTLNE	C	00001004	16	308	318	170													
CCPRTLNG	U	00000055	1	318	169														
CCPRTNAME	C	00001031	8	311	153														
CCPRTNUM	C	00001014	3	309	151														
CCPSW	F	00001098	4	332	140	489	514	539	564	589	614	640	665	690	715	740	765		
					791	816	841	866	891	916	942	967	992	1017	1042	1067			
CTLR0	F	0000040C	4	270	100	101	102	103											
DECNUM	C	00001085	16	328	148	150	157	159	164	166									
E6TADR	A	00000414	4	273	109														
E6TEST	4	00000000	28	356	118														
E6TESTS	F	00001990	4	1079	273														
EDIT	X	00001059	18	323	149	158	165												
ENDTEST	U	000002E4	1	188	114														
E0J	I	000003F0	4	260	191														
E0JPSW	D	000003E0	8	258	260														
FAILCONT	U	000002D4	1	178	173														
FAILED	F	00001000	4	300	180	189													
FAILPSW	D	000003F8	8	262	264														
FAILTEST	I	00000408	4	264	192														
IMAGE	1	00000000	6656	0															
K	U	00000400	1	283	284	285	286												
K64	U	00010000	1	285															
MB	U	00000007	1	360															
MB	U	00100000	1	286															
MSG	I	00000328	4	224	207														
MSGCMD	C	00000372	9	250	237	238													
MSGMSG	C	0000037B	95	251	231	248	229												
MSGMVC	I	0000036C	6	248	235														
MSGOK	I	0000033E	2	233	230														
MSGRET	I	00000358	4	244	241														
MSGSAVE	F	00000360	4	247	227	244													
NEXTE6	U	0000022A	1	111	128	183													
OPNAME	C	0000000A	8	364	153														
PAGE	U	00001000	1	284															
PRT3	C	0000106F	18	326	149	150	151	158	159	160	165	166	167						
R0	U	00000000	1	1117	50	100	103	116	169	179	180	206	208	224	227	229	231		
						233	244	488	513	538	563	588	613	639	664	689	714	739	
						764	790	815	840	865	890	915	941	966	991	1016	1041	1066	
R1	U	00000001	1	1118	123	124	125	140	141	142	143	170	189	190	238	248			
R10	U	0000000A	1	1127	97	98													
R11	U	0000000B	1	1128	120	121	490	515	540	565	590	615	641	666	691	716	741		
					766	792	817	842	867	892	917	943	968	993	1018	1043	1068		
R12	U	0000000C	1	1129	109	112	127	182											
R13	U	0000000D	1	1130															
R14	U	0000000E	1	1131															
R15	U	0000000F	1	1132	171	201	211	212											
R1FUDGE	X	000010A8	8	339															
R1OUTPUT	F	000010E0	8	343															
R2	U	00000002	1	1119	147	148	155	156	157	162	163	164	206	207	208	225	227		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
=AL2(L' MSGMSG)	R	00000422	2	279	229
=F' 1'	F	0000041C	4	277	179
=H' 0'	H	00000420	2	278	224
=XL4' 3'	X	00000418	4	276	142

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	6656	0000- 19FF	0000- 19FF
Regi on		6656	0000- 19FF	0000- 19FF
CSECT	ZVE6TST	6656	0000- 19FF	0000- 19FF

STMT	FILE NAME
1	1
2	2
3	3
4	4
5	5
6	6
7	7
8	8
9	9
10	10
11	11
12	12
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89	89
90	90
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92	92
93	93
94	94
95	95
96	96
97	97
98	98
99	99
100	100

```
1 /devstor/dev/tests/zvector-e6-15-comparedecimal.asm
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**** NO ERRORS FOUND ****